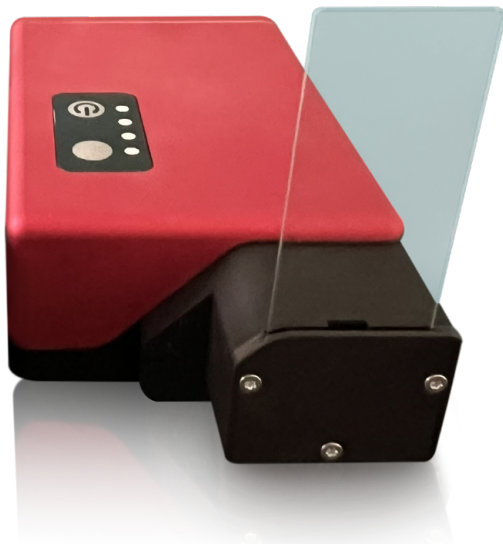


# WP Raman XSB series

## Ultracompact Raman for nonuniform & biological samples



### COMPACT WITHOUT COMPROMISE

High throughput optical bench design based on our patented VPH gratings

Low f#, highly sensitive optical design

Novel 785 nm line-illumination sampling

Raman fingerprint range for rapid ID

Integrated TEC controlled 100 mW single mode laser and probe / sampling optics

High signal reproducibility &  $\text{cm}^{-1}$  stability

SERS substrate & LFA cassette accessories

We're revolutionizing Raman spectroscopy with an ultra-compact, field-deployable system with unprecedented sensitivity at a commercial sensor price point in volume. It combines our signature high-NA optics, patented HD gratings, and an uncooled CMOS camera for high sensitivity and rapid measurements in an ultralight, miniaturized, thermally stable engine. The XSB version of this system uses a Powell lens to create line illumination sampling, which is ideal for distributed sensing of delicate samples, biological lateral flow assays, and SERS substrates (choose from application-specific accessories, or design your own). It's superior Raman - in the palm of your hand.

[Request a demo](#)



# WP Raman XSB series

## STANDARD PRODUCT SPECIFICATIONS & OPTIONS

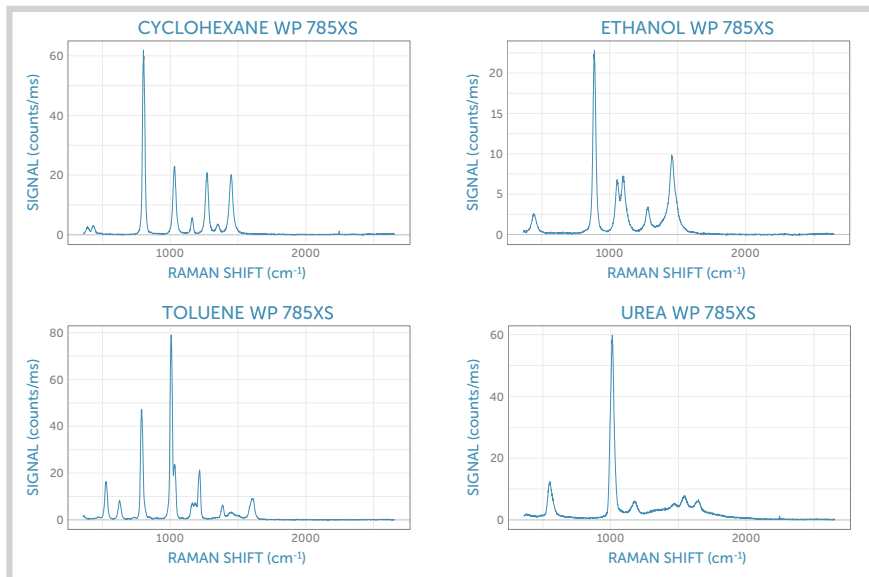
This unique version of our high-sensitivity, f/1.3 XS series optical bench comes with 785 nm excitation imaged into a narrow, precise line to maximize overlap with distributed, inhomogeneous, and delicate samples. It features a more limited fingerprint region and uncooled CMOS detector for reliable spectral capture on low power draw, making it ideal for life science and trace detection applications in the field. All units may be powered and run over USB-C using our ENLIGHTEN™ operating software. The free space output features an SM05 accessory interface with laser interlock, with choice of microscope slide or lateral flow assay cassette holder.

PART NUMBER	SPECTRAL RANGE*	RESOLUTION	LASER + OPTICS	TEC CONTROLLED LASER SPECS
		f/1.3 Input		
WP-785XSB-ILP	400 - 2400 $\text{cm}^{-1}$	15 $\text{cm}^{-1}$	✓	100 mW, single mode

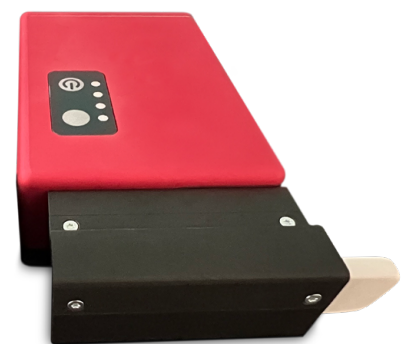
\*Resolution specification for a 20  $\mu\text{m}$  slit, 2 mm in height.

SYSTEM SPECIFICATIONS	
Optical interface	Fully integrated, free-space sampling optics using a Powell lens for line focus onto the sample
Accessory interface	Snap-on magnetic interface with laser interlock
Dimensions & Weight	101 x 72 x 39 mm, approx 300 g (without accessory)
Operating Temperature	0-40°C, non-condensing
Communications	USB 2.0 Type C connector
Software / Control	ENLIGHTEN™ via USB

**CLASS 3B LASER PRODUCT**  
**WARNING – VISIBLE AND INVISIBLE LASER RADIATION**  
**AVOID EXPOSURE TO BEAM**



Sample spectra taken using the WP 785XS-ILP, integration time < 1s.



WP XS Raman system with LFA cassette accessory, which can be used with custom-printed cassette holders to accommodate a variety of lateral flow assay cassettes.